

QM18N20D

N-Channel 200V Fast Switching MOSFET

General Description

The QM18N20D is a high performance N-channel MOSFET which utilizes high voltage technology to provide low $R_{DS(on)}$ and gate charge characteristics. It is ideally suited to support most of SPS, Charger, Adapter and LED lighting applications.

The QM18N20D meets RoHS and Green Product requirements while supporting full function reliability.

Features

- ✓ Super Low Gate Charge
- ✓ Excellent CdV/dt effect decline
- ✓ Green Device Available

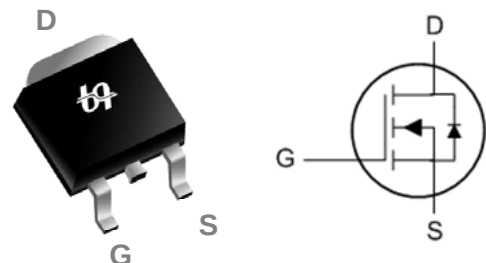
Product Summary

V_{DS}	$R_{DS(ON)}$ max ($V_{GS}=10V$)	I_D ($T_C=25\text{ }^{\circ}C$)
200V	190 m Ω	18A

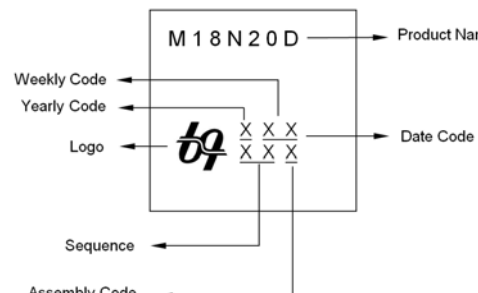
Applications

- ✓ High efficient switched mode power supplies
- ✓ Electronic lamp ballast
- ✓ LCD TV/ Monitor
- ✓ Adapter

Pin Configuration



Ordering Information

Order Number	Package Type	Top Marking
QM18N20D	TO252	

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Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	200	V
V_{GS}	Gate-Source Voltage	± 30	V
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V^1$	18	A
$I_D @ T_C = 100^\circ C$	Continuous Drain Current, $V_{GS} @ 10V^1$	11.4	A
I_{DM}	Pulsed Drain Current ²	36	A
EAS	Single Pulse Avalanche Energy ³	187	mJ
I_{AS}	Avalanche Current	17	A
$P_D @ T_C = 25^\circ C$	Total Power Dissipation ⁴	62.5	W
T_{STG}	Storage Temperature Range	-55 to 150	$^\circ C$
T_J	Operating Junction Temperature Range	-55 to 150	$^\circ C$

Thermal Data

Symbol	Parameter	Typ.	Max.	Unit
$R_{\theta JA}$	Thermal Resistance Junction-ambient (Steady State) ¹	--	62	$^\circ C/W$
$R_{\theta JC}$	Thermal Resistance Junction-Case ¹	--	2	$^\circ C/W$

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N-Channel Electrical Characteristics

N-Channel Electrical Characteristics: (T _J =25 °C, unless otherwise noted)						
Symbol	Parameter	Conditions	Min	Typ	Max	Unit
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D =250uA	200	--	--	V
ΔBV _{DSS} / ΔT _J	BVDSS Temperature Coefficient	Reference to 25°C, I _D =1mA	--	0.17	--	V/°C
R _{DS(ON)}	Static Drain-Source On-Resistance ²	V _{GS} =10V, I _D =12A	--	150	190	mΩ
V _{GS(th)}	Gate Threshold Voltage	V _{GS} =V _{DS} , I _D =250uA	2	--	5	V
ΔV _{GS(th)}	V _{GS(th)} Temperature Coefficient		--	-5.2	--	mV/°C
I _{DSS}	Drain-Source Leakage Current	V _{DS} =160V, V _{GS} =0V, T _J =25°C	--	--	2	uA
I _{GSS}	Gate-Source Leakage Current	V _{GS} =±30V, V _{DS} =0V	--	--	±100	nA
g _{fs}	Forward Transconductance	V _{DS} =5V, I _D =12A	--	18.8	--	S
R _g	Gate Resistance	V _{DS} =0V, V _{GS} =0V, f=1MHz	--	3.2	6.4	Ω
Q _g	Total Gate Charge	V _{DS} =160V, V _{GS} =10V, I _D =12A	--	19.7	27.6	nC
Q _{gs}	Gate-Source Charge		--	6.9	9.7	
Q _{gd}	Gate-Drain Charge		--	4.7	6.6	
t _{d(on)}	Turn-On Delay Time	V _{DS} =100V, V _{GS} =10V, R _G =3.3Ω, I _D =12A	--	10.8	21.6	ns
t _r	Rise Time		--	23	41.4	
t _{d(off)}	Turn-Off Delay Time		--	21	42	
t _f	Fall Time		--	16	32	
C _{iss}	Input Capacitance	V _{DS} =25V, V _{GS} =0V, F=1MHz	--	1190	1666	pF
C _{oss}	Output Capacitance		--	115	161	
C _{rss}	Reverse Transfer Capacitance		--	4	5.6	

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Guaranteed Avalanche Characteristics

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
EAS	Single Pulse Avalanche Energy ⁵	$V_{DD}=50V$, $L=1mH$, $I_{AS}=12A$	93	--	--	mJ

Diode Characteristics

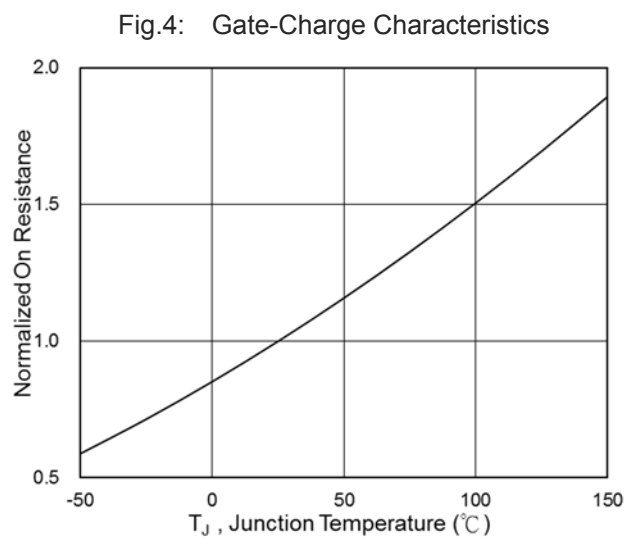
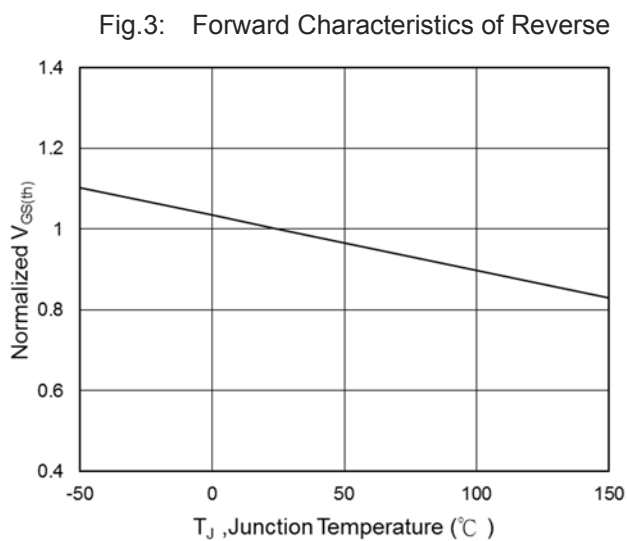
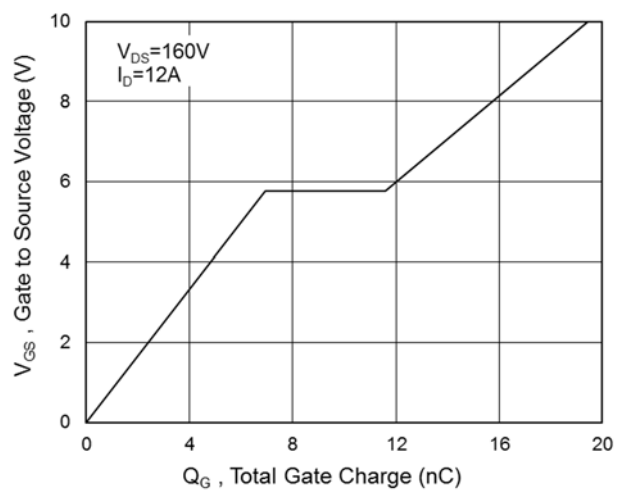
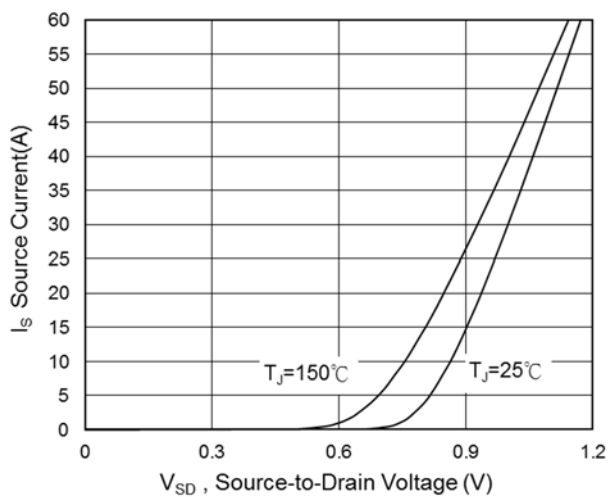
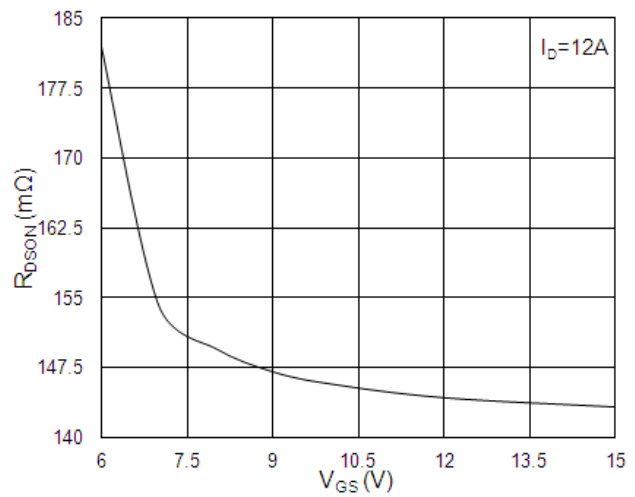
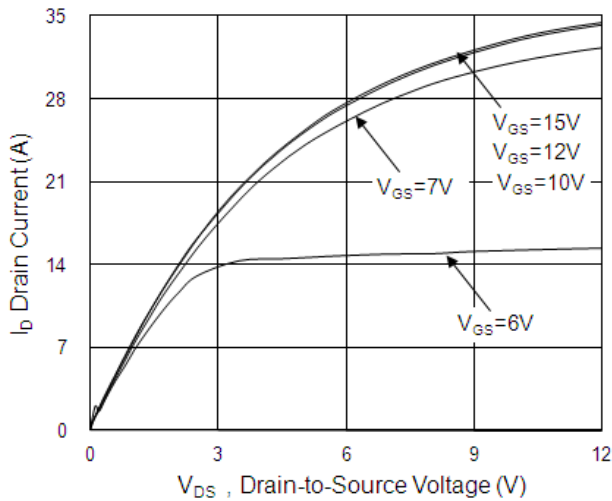
Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
I_S	Continuous Source Current ^{1,6}	$V_G=V_D=0V$, Force Current	--	--	18	A
I_{SM}	Pulsed Source Current ^{2,6}		--	--	36	A
V_{SD}	Diode Forward Voltage ²	$V_{GS}=0V$, $I_S=1A$, $T_J=25^{\circ}C$	--	--	1	V
t_{rr}	Reverse Recovery Time	$I_F=10A$, $di/dt=100A/\mu s$, $T_J=25^{\circ}C$	--	110	--	nS
Q_{rr}	Reverse Recovery Charge		--	525	--	nC

Note:

1. Test data conducted with surface mount attachment to 1 inch², FR-4 board utilizing 2oz copper
2. Pulse Test. Pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$
3. EAS data is a maximum rating. The test condition is $V_{DD}=50V, V_{GS}=10V, L=1mH$
4. The power dissipation is limited by a 150°C maximum junction temperature
5. The Min. value is 100% EAS tested guarantee
6. The data is theoretically the same as I_D and I_{DM} . In real applications, it will be limited by total power

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Typical Characteristics



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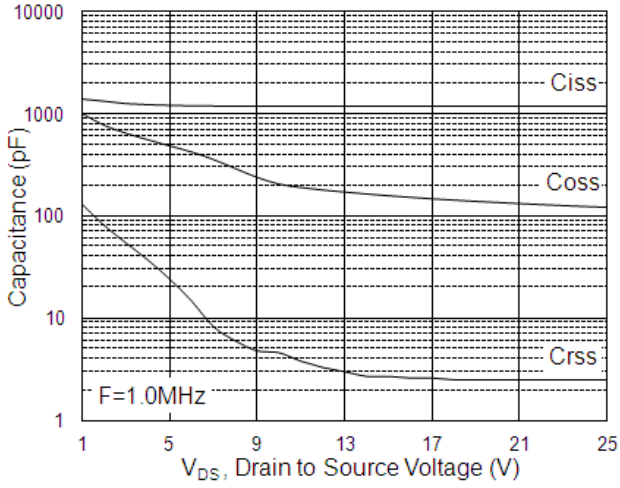


Fig.7: Capacitance

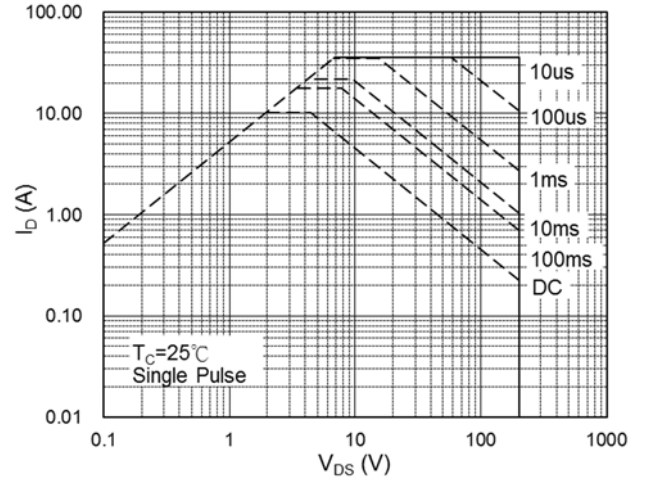


Fig.8: Safe Operating Area

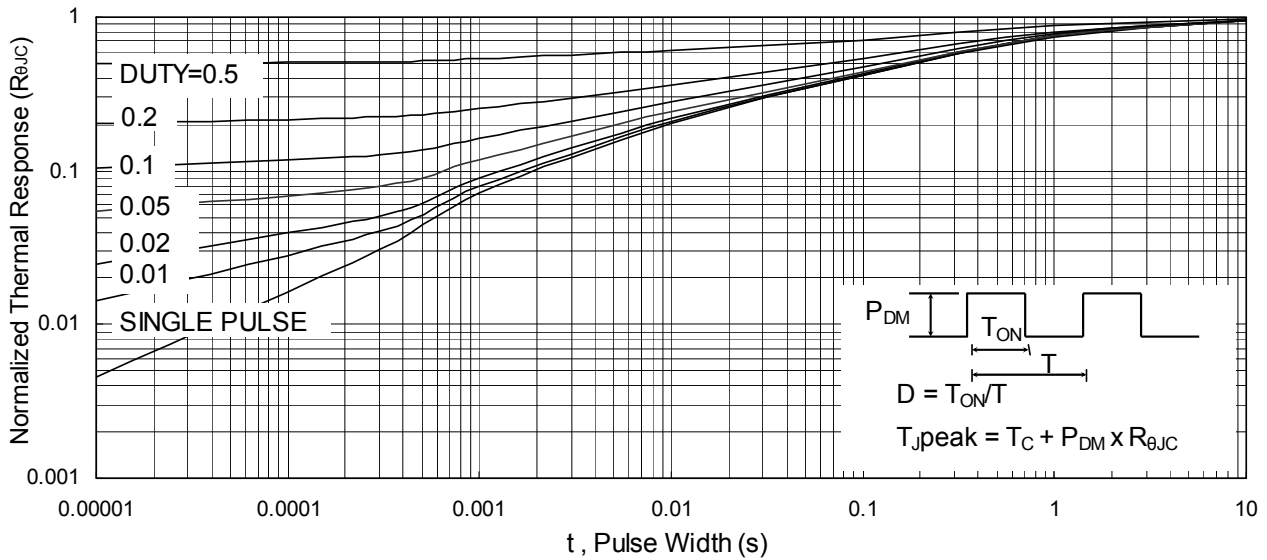


Fig.9: Normalized Maximum Transient Thermal Impedance

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